

Samsung eMMC Product family

eMMC 5.1 Specification compatibility

datasheet

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INTRODUCTION

SAMSUNG eMMC is an embedded MMC solution designed in a BGA package form. eMMC operation is identical to a MMC device and therefore is a simple read and write to memory using MMC protocol v5.1 which is a industry standard.

eMMC consists of NAND flash and a MMC controller. 3V supply voltage is required for the NAND area (VDDF or VCC) whereas 1.8V or 3V dual supply voltage (VDD or VCCQ) is supported for the MMC controller. SAMSUNG eMMC supports 200MHz DDR – up to 400MBps with bus widths of 8 bit in order to improve sequential bandwidth, especially sequential read performance.

There are several advantages of using eMMC. It is easy to use as the MMC interface allows easy integration with any microprocessor with MMC host. Any revision or amendment of NAND is invisible to the host as the embedded MMC controller insulates NAND technology from the host. This leads to faster product development as well as faster times to market.

The embedded flash management software or FTL(Flash Transition Layer) of eMMC manages Wear Leveling, Bad Block Management and ECC. The FTL supports all features of the Samsung NAND flash and achieves optimal performance.

1.0 PRODUCT LIST

[Table 1] Product List

| Capacities | eMMC Part ID | NAND Flash Type | User Density (%) | Power System | Package size | Pin Configuration |
|------------|-----------------|-----------------|------------------|--|-----------------------|-------------------|
| 16 GB | KLMA1JENB-B041 | 128Gb MLC x 1 | 91.0% | - Interface power : VDD (1.70V ~ 1.95V or 2.7V ~ 3.6V) - Memory power : VDDF (2.7V ~ 3.6V) | 11.5mm x 13mm x 0.8mm | 153FBGA |
| 32 GB | KLMBG2JENB-B041 | 128Gb MLC x 2 | | | 11.5mm x 13mm x 1.0mm | |
| 64 GB | KLMDG4JENB-B041 | 128Gb MLC x 4 | | | 11.5mm x 13mm x 1.2mm | |
| 128 GB | KLMDG8JENB-B041 | 128Gb MLC x 8 | | | 11.5mm x 13mm x 1.2mm | |

2.0 KEY FEATURES

- embedded MultiMediaCard Ver. 5.1 compatible.
- SAMSUNG eMMC supports features of eMMC5.1 which are defined in JEDEC Standard
 - Supported Features : Packed command, Cache, Discard, Sanitize, Power Off Notification, Data Tag, Partition types, Context ID, Real Time Clock, Dynamic Device Capacity, Command Queuing, Enhanced Strobe Mode, Secure Write Protection, HS200, HS400, Field Firmware Update.
 - Non-supported Features : Large Sector Size (4KB)
- Full backward compatibility with previous MultiMediaCard system specification (1bit data bus, multi-eMMC systems)
- Data bus width : 1bit (Default), 4bit and 8bit
- MMC I/F Clock Frequency : 0 ~ 200MHz
MMC I/F Boot Frequency : 0 ~ 52MHz
- Temperature : Operation (-25°C ~ 85°C), Storage without operation (-40°C ~ 85°C)
- Power : Interface power → VDD(VCCQ) (1.70V ~ 1.95V or 2.7V ~ 3.6V) , Memory power → VDDF(VCC) (2.7V ~ 3.6V)

IF THERE IS ANY OTHER OPERATION TO IMPLEMENT IN ADDITION TO SPECIFICATION IN THE DATASHEET OR JEDEC STANDARD, PLEASE CONTACT EACH BRANCH OFFICE OR HEADQUARTERS OF SAMSUNG ELECTRONICS.

3.1.1 11.5mm x 13mm x 0.8mm Package Dimension

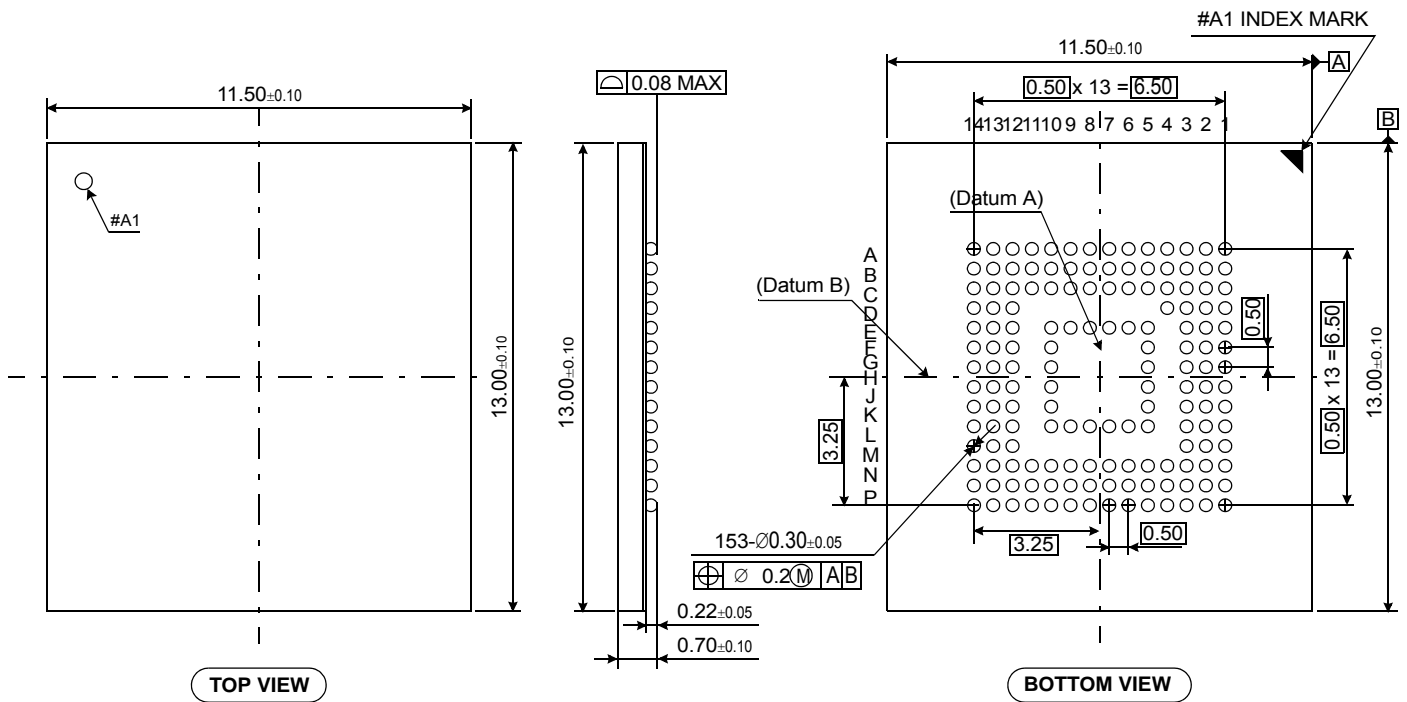


Figure 2. 11.5mm x 13mm x 0.8mm Package Dimension

3.1.2 11.5mm x 13mm x 1.0mm Package Dimension

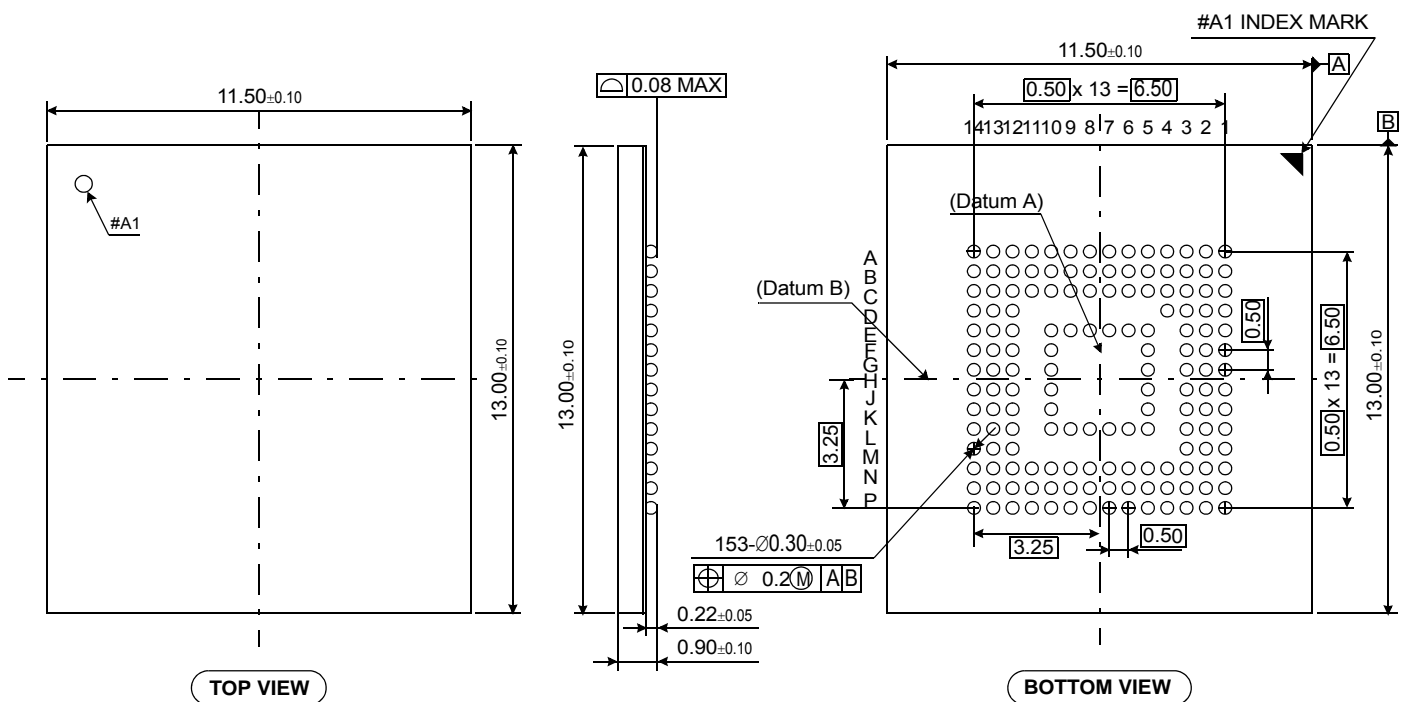


Figure 3. 11.5mm x 13mm x 1.0mm Package Dimension

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3.1.3 11.5mm x 13mm x 1.2mm Package Dimension

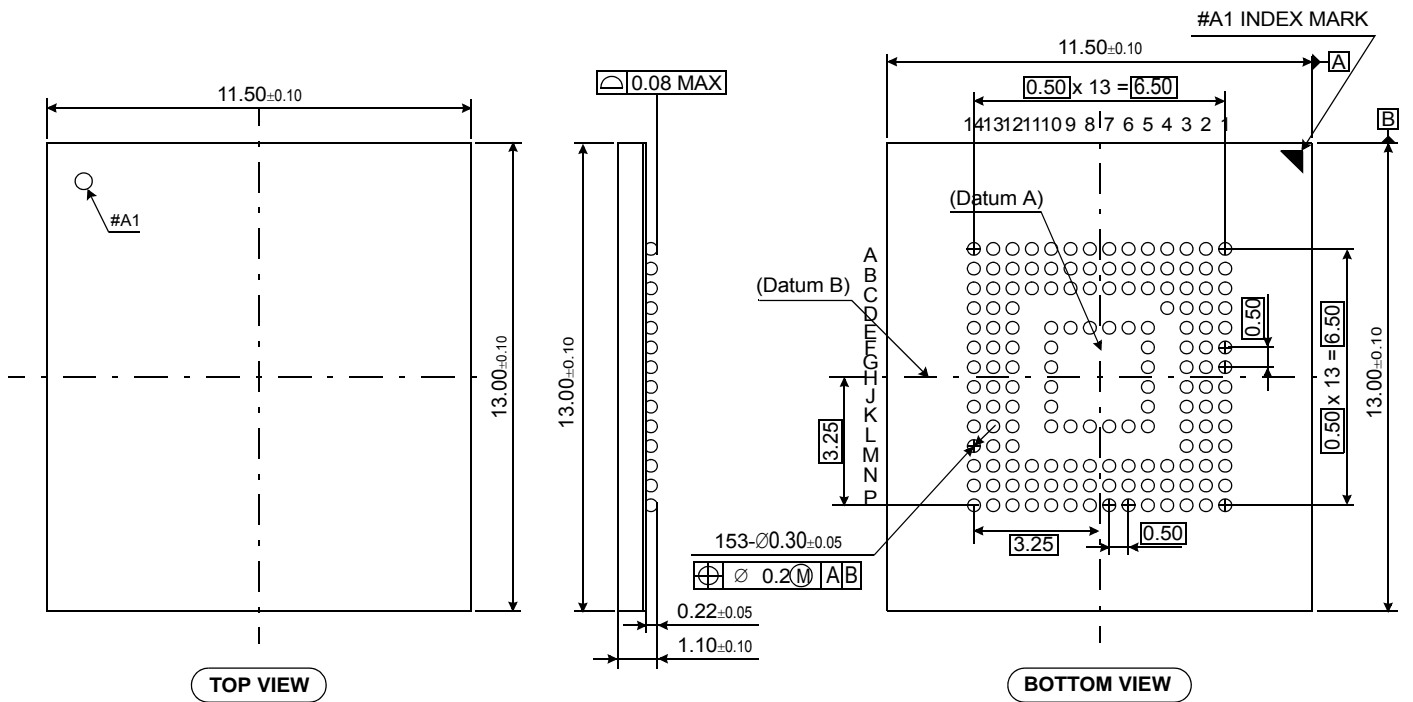


Figure 4. 11.5mm x 13mm x 1.2mm Package Dimension

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3.2 Product Architecture

- eMMC consists of NAND Flash and Controller. V_{DD} (V_{CCQ}) is for Controller power and V_{DDF} (V_{CC}) is for flash power

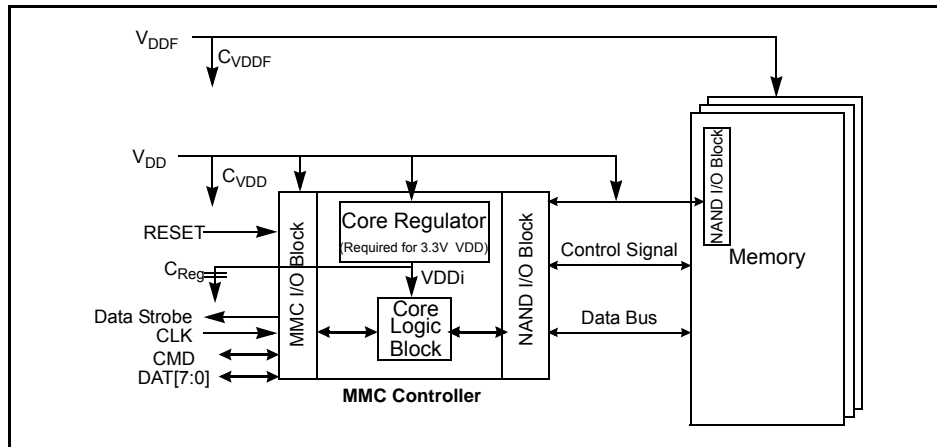


Figure 5. eMMC Block Diagram

| Parameter | Symbol | Min | Max | Unit |
|----------------------|------------|------|------|---------------|
| Voltage 1 | V_{DD} | 1.70 | 1.95 | V |
| Voltage 2 | V_{DDF} | 2.7 | 3.6 | V |
| V_{DD} cap. value | C_{VDD} | 2 | - | μF |
| V_{DDF} cap. Value | C_{VDDF} | 2 | - | μF |
| V_{DDi} cap. Value | C_{Reg} | 1 | 4.7 | μF |

4.0 HS400 mode

eMMC5.0 product supports high speed DDR interface timing mode up to 400MB/s at 200MHz with 1.8V I/O supply.

HS400 mode supports the following features :

- DDR Data sampling method
- CLK frequency up to 200MHz DDR – up to 400Mbps
- Only 8-bits bus width available
- Signaling levels of 1.8V
- Six selectable Drive Strength (refer to the table below)

[Table 3] I/O driver strength types

| Driver Type | HS200 & HS400 Support | Nominal Impedance | Approximated driving capability compared to Type-0 | Remark |
|-------------|-----------------------|-------------------|--|---|
| 0 | Default | 50Ω | x1 | Default Driver Type. Supports up to 200MHz operation. |
| 1 | Optional | 33Ω | x1.5 | Supports up to 200MHz Operation. |
| 2 | Optional | 66Ω | x0.75 | The weakest driver that supports up to 200MHz operation. |
| 3 | Optional | 100Ω | x0.5 | For low noise and low EMI systems. Maximal operating frequency is decided by Host design. |
| 4 | Optional | 40Ω | x1.2 | Supports up to 200MHz DDR operation |

NOTE:

1) Support of Driver Type-0 is default for HS200 & HS400 Device, while supporting Driver types 1~4 are optional for HS200 & HS400 Device.

[Table 4] Device type values (EXT_CSD register : DEVICE_TYPE [196])

| Bit | Device Type | Supportability |
|-----|---|----------------|
| 7 | HS400 Dual Data Rate eMMC @ 200 MHz - 1.2V I/O | Not support |
| 6 | HS400 Dual Data Rate eMMC @ 200 MHz - 1.8V I/O | Support |
| 5 | HS200 Single Data Rate eMMC @ 200 MHz - 1.2V I/O | Not support |
| 4 | HS200 Single Data Rate eMMC @ 200 MHz - 1.8V I/O | Support |
| 3 | High-Speed Dual Data Rate eMMC @ 52MHz - 1.2V I/O | Not support |
| 2 | High-Speed Dual Data Rate eMMC @ 52MHz - 1.8V or 3V I/O | Support |
| 1 | High-Speed eMMC @ 52MHz - at rated device voltage(s) | Support |
| 0 | High-Speed eMMC @ 26MHz - at rated device voltage(s) | Support |

[Table 5] Extended CSD revisions (EXT_CSD register : EXT_CSD_REV [192])

| Value | Timing Interface | EXT_CSD Register Value |
|-------|------------------------------------|------------------------|
| 255-8 | Reserved | - |
| 8 | Revision 1.8 (for MMC V5.1) | 0x08 |
| 7 | Revision 1.7 (for MMC V5.0) | - |
| 6 | Revision 1.6 (for MMC V4.5, V4.51) | - |
| 5 | Revision 1.5 (for MMC V4.41) | - |
| 4 | Revision 1.4 (Obsolete) | - |
| 3 | Revision 1.3 (for MMC V4.3) | - |
| 2 | Revision 1.2 (for MMC V4.2) | - |
| 1 | Revision 1.1 (for MMC V4.1) | - |
| 0 | Revision 1.0 (for MMC V4.0) | - |

[Table 6] High speed timing values (EXT_CSD register : HS_TIMING [185])

| Value | Timing Interface | Supportability |
|-------|--|----------------|
| 0x0 | Selecting backwards compatibility interface timing | Support |
| 0x1 | High Speed | Support |
| 0x2 | HS200 | Support |
| 0x3 | HS400 | Support |

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5.0 New eMMC5.1 Features

5.1 Overview

| New Feature | JEDEC | Support |
|------------------------------|-----------|---------|
| Cache Flushing Report | Mandatory | Yes |
| Background operation control | Mandatory | Yes |
| Command Queuing | Optional | Yes |
| Enhanced Strobe | Optional | Yes |
| RPMB Throughput improve | Optional | Yes |
| Secure Write Protection | Optional | Yes |

5.2 Command Queuing

To facilitate command queuing in eMMC, the device manages an internal task queue that the host can queue during data transfer tasks.

Every task is issued by the host and initially queued as pending. The device works to prepare pending tasks for execution. When a task is ready for execution, its state changes to "ready for execution".

The host tracks the state of all queued tasks and may order the execution of any task, marked as "ready for execution", by sending a command indicating its task ID. The device executes the data transfer transaction after receiving the execute command(CMD46/CMD47)

5.2.1 CMD Set Description

[Table 7] CMD Set Description and Details

| CMD | Type | Argument | Abbreviation | Purpose |
|-------|---------|---|---------------------|---|
| CMD44 | ac/R1 | [31] Reliable Write Request [30] DAT_DIR - "0" write / "1" read [29] tag request [28:25] context ID [24] forced programming [23] Priority: "0" simple / "1" high [20:16] TASK ID [15:0] number of blocks | QUEUED_TASK_PARAMS | Define direction of operation (Read or Write) and Set high priority CMD Queue with task ID |
| CMD45 | ac/R1 | [31:0] Start block address | QUEUED_TASK_ADDRESS | Indicate data address for Queued CMD |
| CMD46 | adtc/R1 | [20:16] TASK ID | EXECUTE_READ_TASK | (Read) Transmit the requested number of data blocks |
| CMD47 | adtc/R1 | [20:16] TASK ID | EXECUTE_WRITE_TASK | (Write) Transmit the requested number of data blocks |
| CMD48 | ac/R1b | [20:16] Task ID [3:0] TM op-code | CMDQ_TASK_MGMT | Reset a specific task or entire queue. [20:16] when TM op-code = 2h these bits represent TaskID. When TM op-code = 1h these bits are reserved." |

5.2.2 New Response : QSR (Queue Status Register)

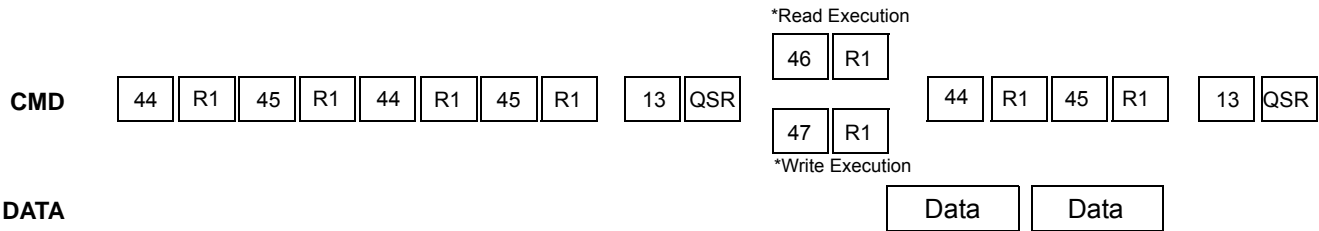
The 32-bit Queue Status Register (QSR) carries the state of tasks in the queue at a specific point in time. The host has read access to this register through device response to SEND_STATUS command (CMD13 with bit[15]="1"), R1's argument will be the 32-bit Queue Status Register (QSR). Every bit in the QSR represents the task whose ID corresponds to the bit index. If bit QSR[i] = "0", then the queued task with a Task ID i is not ready for execution. The task may be queued and pending, or the Task ID is unused. If bit QSR[i] = "1", then the queued task with Task ID i is ready for execution.

5.2.3 Send Status : CMD13

CMD13 for reading the Queue Status Register (QSR) by the host. If bit[15] in CMD13's argument is set to 1, then the device shall send an R1 Response with the QSR instead of the Device Status. * There is still legacy CMD13 with R` response

5.2.4 Mechanism of CMD Queue operation

Host issues CMD44 with Task ID number, Sector, Count, Direction, Priority to the device followed by CMD45 and host checks the Queue Status check with CMD13 [15]bits to 1. After that host issues CMD46 for Read or CMD47 for write During CMD queue operation, CMD44/CMD45 is able to be issued at anytime when the CMD line is not in use



5.2.5 CMD Queue Register description

Configuration and capability structures shall be added to the EXT_CSD register, as described below

[Table 8] CMD Queuing Support (EXT_CSD register : CMDQ_SUPPORT [308])

| Bit7 | Bit6 | Bit5 | Bit4 | Bit | Bit2 | Bit1 | Bit0 |
|----------|------|------|------|-----|------|------|--------------------------|
| Reserved | | | | | | | CMD Queue supportability |

This field indicates whether the device supports command queuing or not

0x0: CMD Queue function is not supported

0x1: CMD Queue function is supported

[Table 9] Command Queue Mode Enable(EXT_CSD register : CMDQ_MODE_EN [15])

| Bit7 | Bit6 | Bit5 | Bit4 | Bit | Bit2 | Bit1 | Bit0 |
|----------|------|------|------|-----|------|------|------|
| Reserved | | | | | | | - |

This field is used by the host enable command queuing

0x0: Queue function is not enabled

0x1: Queue function is enabled

[Table 10] CMD Queuing Depth(EXT_CSD register : CMDQ_DEPTH [307])

| Bit7 | Bit6 | Bit5 | Bit4 | Bit | Bit2 | Bit1 | Bit0 |
|----------|------|------|------|-----|------|------|------|
| Reserved | | | | N | | | |

This field is used to calculate the depth of the queue supported by the device

Bit encoding:

[7:5]: Reserved

[4:0]: N,a parameter used to calculate the Queue Depth of task queue in the device.

Queue Depth = N+1.

5.3 Enhanced Strobe Mode

This product supports Enhanced Strobe in HS400 mode and refer to the details as described in eMMC5.1 JEDEC standard

5.4 RPMB Throughput improve

[Table 11] Related parameter register in EXT_CSD : WR_REL_PARAM [166]

| Name | Field | Bit | Type |
|------------------------------|----------------|-----|------|
| Enhanced RPMB Reliable Write | EN_RPMB_REL_WR | 4 | R |

Bit[4]: EN_RPMB_REL_WR(R)

0x0: RPMB transfer size is either 256B (single 512B frame) or 512B (Two 512B frame).

0 x1: RPMB transfer size is either 256B (single 512B frame), 512B (Two 512B frame), or 8KB(Thirty two 512B frames).

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5.5 Secure Write Protection

Configuration and capability structures shall be added to the EXT_CSD register and Authenticated Device Configuration Area as described below

[Table 12] Parameter register in EXT_CSD : SECURE_WP_INFO [211]

| Bit7 | Bit6 | Bit5 | Bit4 | Bit | Bit2 | Bit1 | Bit0 |
|----------|------|------|------|-----|------|---------------------|-------------------|
| Reserved | | | | | | SECURE_WP_EN_STATUS | SECURE_WP_SUPPORT |

Bit[7:2]: Reserved

Bit[1]: SECURE_WP_EN_STATUS(R)

0x0: Legacy Write Protection mode.

0x1: Secure Write Protection mode.

Bit[0]: SECURE_WP_SUPPORT(R)

0x0: Secure Write Protection is NOT supported by this device

0x1: Secure Write Protection is supported by this device

[Table 13] Authenticated Device Configuration Area[1] : SECURE_WP_MODE_ENABLE

| Bit7 | Bit6 | Bit5 | Bit4 | Bit | Bit2 | Bit1 | Bit0 |
|----------|------|------|------|-----|------|------|------|
| Reserved | | | | | | | 0x00 |

Bit[7:1] : Reserved

Bit[0] : SECURE_WP_EN (R/W/E)

The default value of this field is 0x0.

- 0x0 : Legacy Write Protection mode, i.e., TMP_WRITE_PROTECT[12] , PERM_WRITE_PROTECT[13] is updated by CMD27. USER_WP[171], BOOT_WP[173] and BOOT_WP_STATUS[174] are updated by CMD6.
- 0x1 : Secure Write Protection mode. The access to the write protection related EXT_CSD and CSD fields depends on the value of SECURE_WP_MASK bit in SECURE_WP_MODE_CONFIG field.

[Table 14] Authenticated Device Configuration Area[2] : SECURE_WP_MODE_CONFIG

| Bit7 | Bit6 | Bit5 | Bit4 | Bit | Bit2 | Bit1 | Bit0 |
|----------|------|------|------|-----|------|------|------|
| Reserved | | | | | | | 0x00 |

Bit[7:1] : Reserved

Bit[0] : SECURE_WP_MASK (R/W/E_P)

The default value of this field is 0x0.

- 0x0: Disabling updating WP related EXT_CSD and CSD fields. CMD27 (Program CSD) will generate generic error for setting TMP_WRITE_PROTECT[12] , PERM_WRITE_PROTECT[13]. CMD6 for updating USER_WP[171], BOOT_WP[173] and BOOT_WP_STATUS[174] generates SWITCH_ERROR. If a force erase command is issued, the command will fail (Device stays locked) and the LOCK_UNLOCK_FAILED error bit will be set in the status register. If CMD28 or CMD29 is issued, then generic error will be occurred. Power-on Write Protected boot partitions will keep protected mode after power failure, H/W reset assertion and any CMD0 reset. The device keeps the current value of BOOT_WP_STATUS in the EXT_CSD register to be same after power cycle, H/W reset assertion, and any CMD0 reset.
- 0x1: Enabling updating WP related EXT_CSD and CSD fields. I.e TMP_WRITE_PROTECT[12] , PERM_WRITE_PROTECT[13] , USER_WP[171], BOOT_WP[173] and BOOT_WP_STATUS[174] are accessed using CMD6, CMD8 and CMD27. If a force erase command is issued and accepted, then ALL THE DEVICE CONTENT WILL BE ERASED including the PWD and PWD_LEN register content and the locked Device will get unlocked. If a force erase command is issued and power-on protected or a permanently-write-protected write protect groups exist on the device, the command will fail (Device stays locked) and the LOCK_UNLOCK_FAILED error bit will be set in the status register. An attempt to force erase on an unlocked Device will fail and LOCK_UNLOCK_FAILED error bit will be set in the status register. Write Protection is applied to the WPG indicated by CMD28 with the WP type indicated by the bit[2] and bit[0] of USER_WP[171]. All temporary WP Groups and power-on Write Protected boot partitions become writable/erasable temporarily which means write protect type is not changed. All power-on and permanent WP Groups in user area will not become writable/erasable temporarily. Those temporarily writable/erasable area will become write protected when this bit is cleared to 0x0 by the host or when there is power failure, H/W reset assertion and any CMD0 reset. The device keeps the current value of BOOT_WP_STATUS in the EXT_CSD register to be same after power cycle, H/W reset assertion, and any CMD0 reset.

6.0 Technical Notes

6.1 S/W Algorithm

6.1.1 Partition Management

The device initially consists of two Boot Partitions and RPMB Partition and User Data Area.

The User Data Area can be divided into four General Purpose Area Partitions and User Data Area partition. Each of the General Purpose Area partitions and a section of User Data Area partition can be configured as enhanced partition.

6.1.1.1 Boot Area Partition and RPMB Area Partition

Boot Partition size & RPMB Partition Size are set by the following command sequence :

[Table 15] Setting sequence of Boot Area Partition size and RPMB Area Partition size

| Function | Command | Description |
|----------------------------|-----------------------|---|
| Partition Size Change Mode | CMD62(0xEFAC62EC) | Enter the Partition Size Change Mode |
| Partition Size Set Mode | CMD62(0x00CBAEA7) | Partition Size setting mode |
| Set Boot Partition Size | CMD62(BOOT_SIZE_MULT) | Boot Partition Size value |
| Set RPMB Partition Size | CMD62(RPMB_SIZE_MULT) | RPMB Partition Size value F/W Re-Partition is executed in this step. |
| Power Cycle | | |

Boot partition size is calculated as (128KB * BOOT_SIZE_MULT)

The size of Boot Area Partition 1 and 2 can not be set independently. It is set as same value.

RPMB partition size is calculated as (128KB * RPMB_SIZE_MULT).

In RPMB partition, CMD 0, 6, 8, 12, 13, 15, 18, 23, 25 are admitted.

Access Size of RPMB partition is defined as the below:

[Table 16] REL_WR_SEC_C value for write operation on RPMB partition

| REL_WR_SEC_C | Description |
|------------------|--|
| REL_WR_SEC_C = 1 | Access sizes 256B and 512B supported to RPMB partition |
| REL_WR_SEC_C > 1 | Access sizes up to REL_WR_SEC_C * 512B supported to RPMB partition with 256B granularity |

Any undefined set of parameters or sequence of commands results in failure access.

If the failure is in data programming case, the data is not programmed. And if the failure occurs in data read case, the read data is '0x00'.

6.1.1.2 Enhanced Partition (Area)

SAMSUNG eMMC adopts Enhanced User Data Area as SLC Mode. Therefore when master adopts some portion as enhanced user data area in User Data Area, that area occupies double size of original set up size. (ex> if master set 1MB for enhanced mode, total 2MB user data area is needed to generate 1MB enhanced area)

Max Enhanced User Data Area size is defined as (MAX_ENH_SIZE_MULT x HC_WP_GRP_SIZE x HC_ERASE_GRP_SIZE x 512kBytes)

6.1.2 Boot operation

Device supports not only boot mode but also alternative boot mode. Device supports high speed timing and dual data rate during boot.

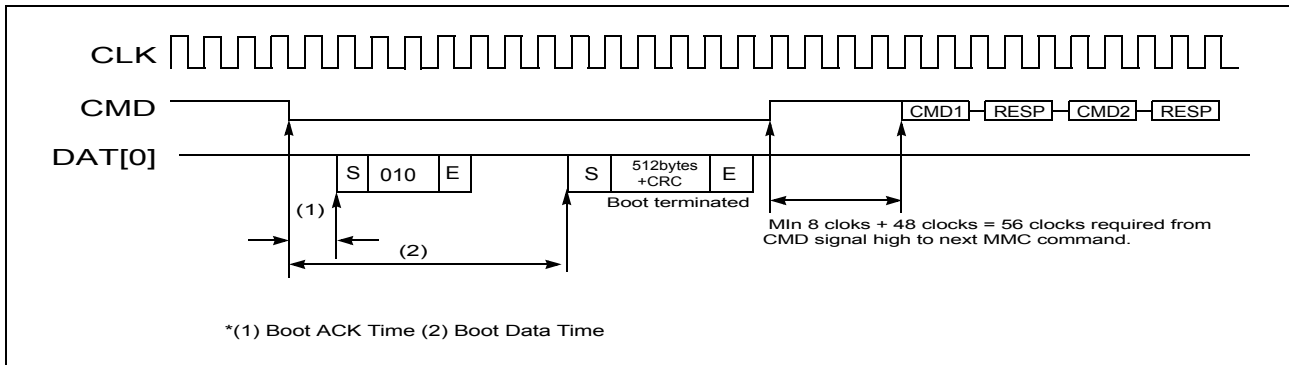


Figure 6. embedded MultiMediaCard state diagram (boot mode)

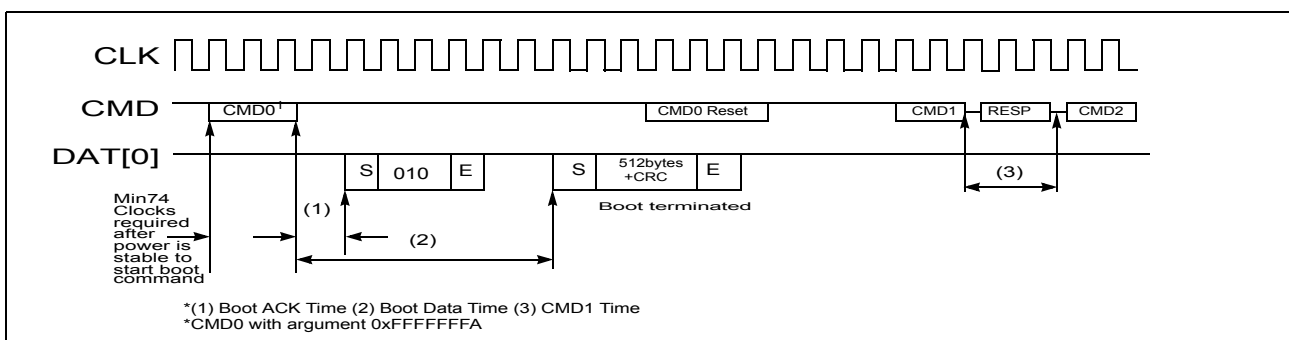


Figure 7. embedded MultiMediaCard state diagram (alternative boot mode)

[Table 17] Boot ack, boot data and initialization Time

| Timing Factor | Value |
|---------------------------------------|----------|
| (1) Boot ACK Time | < 50 ms |
| (2) Boot Data Time | < 100 ms |
| (3) Initialization Time ¹⁾ | < 3 secs |

NOTE:

- 1) This initialization time includes partition setting, Please refer to INI_TIMEOUT_AP in 6.4 Extended CSD Register. Normal initialization time (without partition setting) is completed within 1sec

6.1.3 User Density

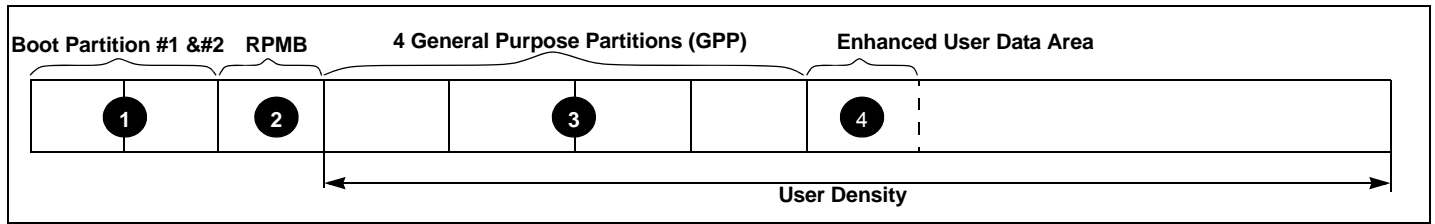


Figure 8. Example of Partition Configuration

[Table 18] Capacity according to partition

| | Boot partition 1 | Boot partition 2 | RPMB |
|----------|------------------|------------------|---------|
| Default. | 4,096KB | 4,096KB | 4,096KB |
| Max. | 4,096KB | 4,096KB | 4,096KB |

For example, 32MB in the SLC Mode requires 64MB in MLC.
This results in decreasing of user density

[Table 19] Maximum Enhanced Partition Size

| Device | Max. Enhanced Partition Size |
|--------|------------------------------|
| 16 GB | 7,809,794,048 Byte |
| 32 GB | 15,627,976,704 Byte |
| 64 GB | 31,264,342,016 Byte |
| 128 GB | 62,528,684,032 Byte |

[Table 20] User Density Size

| Device | User Density Size |
|--------|----------------------|
| 16 GB | 15,634,268,160 Byte |
| 32 GB | 31,268,536,320 Byte |
| 64 GB | 62,537,072,640 Byte |
| 128 GB | 125,069,950,976 Byte |

6.1.4 Auto Power Saving Mode

If host does not issue any command during a certain duration (1ms), after previously issued command is completed, the device enters "Power Saving mode" to reduce power consumption.

At this time, commands arriving at the device while it is in power saving mode will be serviced in normal fashion

[Table 21] Auto Power Saving Mode enter and exit

| Mode | Enter Condition | Escape Condition |
|------------------------|---|----------------------------|
| Auto Power Saving Mode | When previous operation which came from Host is completed and no command is issued during a certain time. | If Host issues any command |

[Table 22] Auto Power Saving Mode and Sleep Mode

| | Auto Power Saving Mode | Sleep Mode |
|----------------|------------------------|------------|
| NAND Power | ON | OFF |
| GotoSleep Time | < 4ms | < 1ms |

IF THERE IS ANY OTHER OPERATION TO IMPLEMENT IN ADDITION TO SPECIFICATION IN THE DATASHEET OR JEDEC STANDARD, PLEASE CONTACT EACH BRANCH OFFICE OR HEADQUARTERS OF SAMSUNG ELECTRONICS.

6.1.5 Performance

[Table 23] Performance

| Density | Partition Type | Performance | |
|---------|----------------|-------------|--------------|
| | | Read(MB/s) | Write (MB/s) |
| 16GB | General | 285 | 40 |
| 32GB | | 310 | 70 |
| 64GB | | 310 | 140 |
| 128GB | | 310 | 140 |
| 16GB | Enhanced | 295 | 80 |
| 32GB | | 320 | 150 |
| 64GB | | 320 | 245 |
| 128GB | | 320 | 245 |

* Test Condition : Bus width x8, HS400, 512KB data transfer, Packed Off, Cache On, w/o file system overhead, measured on Samsung's internal board

7.0 REGISTER VALUE

7.1 OCR Register

The 32-bit operation conditions register stores the VDD voltage profile of the eMMC. In addition, this register includes a status information bit. This status bit is set if the eMMC power up procedure has been finished. The OCR register shall be implemented by all eMMCs.

[Table 24] OCR Register

| OCR bit | VDD voltage window ² | Register Value |
|---------|--|--|
| [6:0] | Reserved | 00 00000b |
| [7] | 1.70 - 1.95 | 1b |
| [14:8] | 2.0-2.6 | 000 0000b |
| [23:15] | 2.7-3.6 | 1 1111 1111b |
| [28:24] | Reserved | 0 0000b |
| [30:29] | Access Mode | 00b (byte mode) 10b (sector mode) -[*Higher than 2GB only] |
| [31] | eMMC power up status bit (busy) ¹ | |

NOTE :

- 1) This bit is set to LOW if the eMMC has not finished the power up routine
- 2) The voltage for internal flash memory(VDDF) should be 2.7-3.6v regardless of OCR Register value.

7.2 CID Register

[Table 25] CID Register

| Name | Field | Width | CID-slice | CID Value |
|-----------------------|-------|-------|-----------|------------------------|
| Manufacturer ID | MID | 8 | [127:120] | 0x15 |
| Reserved | | 6 | [119:114] | --- |
| Card/BGA | CBX | 2 | [113:112] | 0x01 |
| OEM/Application ID | OID | 8 | [111:104] | --- ¹ |
| Product name | PNM | 48 | [103:56] | See Product name table |
| Product revision | PRV | 8 | [55:48] | --- ² |
| Product serial number | PSN | 32 | [47:16] | --- ³ |
| Manufacturing date | MDT | 8 | [15:8] | --- ⁴ |
| CRC7 checksum | CRC | 7 | [7:1] | --- ⁵ |
| not used, always '1' | - | 1 | [0:0] | --- |

NOTE :

- 1),4),5) description are same as e.MMC JEDEC standard
- 2) PRV is composed of the revision count of controller and the revision count of F/W patch
- 3) A 32 bits unsigned binary integer. (Random Number)

7.2.1 Product name table (In CID Register)

[Table 26] Product name table

| Part Number | Density | Product Name in CID Register (PNM) |
|-----------------|---------|------------------------------------|
| KLMAG1JENB-B041 | 16 GB | 0 x 414A4E423452 |
| KLMBG2JENB-B041 | 32 GB | 0 x 424A4E423452 |
| KLMCG4JENB-B041 | 64 GB | 0 x 434A4E423452 |
| KLMDG8JENB-B041 | 128 GB | 0 x 444A4E423452 |

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7.3 CSD Register

The Card-Specific Data register provides information on how to access the eMMC contents. The CSD defines the data format, error correction type, maximum data access time, data transfer speed, whether the DSR register can be used etc. The programmable part of the register (entries marked by W or E, see below) can be changed by CMD27. The type of the entries in the table below is coded as follows:

R : Read only

W: One time programmable and not readable.

R/W: One time programmable and readable.

W/E : Multiple writable with value kept after power failure, H/W reset assertion and any CMD0 reset and not readable.

R/W/E: Multiple writable with value kept after power failure, H/W reset assertion and any CMD0 reset and readable.

R/W/C_P: Writable after value cleared by power failure and H/W reset assertion (the value not cleared by CMD0 reset) and readable.

R/W/E_P: Multiple writable with value reset after power failure, H/W reset assertion and any CMD0 reset and readable.

W/E/_P: Multiple writable with value reset after power failure, H/W reset assertion and any CMD0 reset and not readable.

[Table 27] CSD Register

| Name | Field | Width | Cell Type | CSD-slice | CSD Value | | | |
|--|--------------------|-------|-----------|-----------|-----------|------|------|-------|
| | | | | | 16GB | 32GB | 64GB | 128GB |
| CSD structure | CSD_STRUCTURE | 2 | R | [127:126] | 0x03 | | | |
| System specification version | SPEC_VERS | 4 | R | [125:122] | 0x04 | | | |
| Reserved | - | 2 | R | [121:120] | - | | | |
| Data read access-time 1 | TAAC | 8 | R | [119:112] | 0x27 | | | |
| Data read access-time 2 in CLK cycles (NSAC*100) | NSAC | 8 | R | [111:104] | 0x01 | | | |
| Max. bus clock frequency | TRAN_SPEED | 8 | R | [103:96] | 0x32 | | | |
| Device command classes | CCC | 12 | R | [95:84] | 0xF5 | | | |
| Max. read data block length | READ_BL_LEN | 4 | R | [83:80] | 0x09 | | | |
| Partial blocks for read allowed | READ_BL_PARTIAL | 1 | R | [79:79] | 0x00 | | | |
| Write block misalignment | WRITE_BLK_MISALIGN | 1 | R | [78:78] | 0x00 | | | |
| Read block misalignment | READ_BLK_MISALIGN | 1 | R | [77:77] | 0x00 | | | |
| DSR implemented | DSR_IMP | 1 | R | [76:76] | 0x00 | | | |
| Reserved | - | 2 | R | [75:74] | - | | | |
| Device size | C_SIZE | 12 | R | [73:62] | 0xFFFF | | | |
| Max. read current @ VDD min | VDD_R_CURR_MIN | 3 | R | [61:59] | 0x06 | | | |
| Max. read current @ VDD max | VDD_R_CURR_MAX | 3 | R | [58:56] | 0x06 | | | |
| Max. write current @ VDD min | VDD_W_CURR_MIN | 3 | R | [55:53] | 0x06 | | | |
| Max. write current @ VDD max | VDD_W_CURR_MAX | 3 | R | [52:50] | 0x06 | | | |
| Device size multiplier | C_SIZE_MULT | 3 | R | [49:47] | 0x07 | | | |
| Erase group size | ERASE_GRP_SIZE | 5 | R | [46:42] | 0x1F | | | |
| Erase group size multiplier | ERASE_GRP_MULT | 5 | R | [41:37] | 0x1F | | | |
| Write protect group size | WP_GRP_SIZE | 5 | R | [36:32] | 0x0F | | | |
| Write protect group enable | WP_GRP_ENABLE | 1 | R | [31:31] | 0x01 | | | |
| Manufacturer default ECC | DEFAULT_ECC | 2 | R | [30:29] | 0x00 | | | |
| Write speed factor | R2W_FACTOR | 3 | R | [28:26] | 0x03 | | | |
| Max. write data block length | WRITE_BL_LEN | 4 | R | [25:22] | 0x09 | | | |
| Partial blocks for write allowed | WRITE_BL_PARTIAL | 1 | R | [21:21] | 0x00 | | | |
| Reserved | - | 4 | R | [20:17] | - | | | |
| Content protection application | CONTENT_PROT_APP | 1 | R | [16:16] | 0x00 | | | |
| File format group | FILE_FORMAT_GRP | 1 | R/W | [15:15] | 0x00 | | | |
| Copy flag (OTP) | COPY | 1 | R/W | [14:14] | 0x01 | | | |
| Permanent write protection | PERM_WRITE_PROTECT | 1 | R/W | [13:13] | 0x00 | | | |
| Temporary write protection | TMP_WRITE_PROTECT | 1 | R/W/E | [12:12] | 0x00 | | | |
| File format | FILE_FORMAT | 2 | R/W | [11:10] | 0x00 | | | |
| ECC code | ECC | 2 | R/W/E | [9:8] | 0x00 | | | |
| CRC | CRC | 7 | R/W/E | [7:1] | - | | | |
| Not used, always '1' | - | 1 | — | [0:0] | - | | | |

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7.4 Extended CSD Register

The Extended CSD register defines the eMMC properties and selected modes. It is 512 bytes long.

The most significant 320 bytes are the Properties segment, which defines the eMMC capabilities and cannot be modified by the host. The lower 192 bytes are the Modes segment, which defines the configuration the eMMC is working in. These modes can be changed by the host by means of the SWITCH command.

R : Read only

W: One time programmable and not readable.

R/W: One time programmable and readable.

W/E : Multiple writable with value kept after power failure, H/W reset assertion and any CMD0 reset and not readable.

R/W/E: Multiple writable with value kept after power failure, H/W reset assertion and any CMD0 reset and readable.

R/W/C_P: Writable after value cleared by power failure and HW/ rest assertion (the value not cleared by CMD0 reset) and readable.

R/W/E_P: Multiple writable with value reset after power failure, H/W reset assertion and any CMD0 reset and readable.

W/E/_P: Multiple writable with value reset after power failure, H/W reset assertion and any CMD0 reset and not readable

[Table 28] Extended CSD Register

| Name | Field | Size (Bytes) | Cell Type | CSD slice | CSD Value | | | |
|---|---|--------------|-----------|-----------|------------|------|------|-------|
| | | | | | 16GB | 32GB | 64GB | 128GB |
| Properties Segment | | | | | | | | |
| Reserved ¹ | | 6 | - | [511:506] | - | | | |
| Extended Security Commands Error | EXT_SECURITY_ERR | 1 | R | [505] | 0x00 | | | |
| Supported Command Sets | S_CMD_SET | 1 | R | [504] | 0x01 | | | |
| HPI features | HPI_FEATURES | 1 | R | [503] | 0x01 | | | |
| Background operations support | BKOPS_SUPPORT | 1 | R | [502] | 0x01 | | | |
| Max packed read commands | MAX_PACKED_READS | 1 | R | [501] | 0x3F | | | |
| Max packed write commands | MAX_PACKED_WRITES | 1 | R | [500] | 0x3F | | | |
| Data Tag Support | DATA_TAG_SUPPORT | 1 | R | [499] | 0x01 | | | |
| Tag Unit Size | TAG_UNIT_SIZE | 1 | R | [498] | 0x02 | | | |
| Tag Resources Size | TAG_RES_SIZE | 1 | R | [497] | 0x00 | | | |
| Context management capabilities | CONTEXT_CAPABILITIES | 1 | R | [496] | 0x05 | | | |
| Large Unit size | LARGE_UNIT_SIZE_M1 | 1 | R | [495] | 0x07 | | | |
| Extended partitions attribute support | EXT_SUPPORT | 1 | R | [494] | 0x03 | | | |
| Supported modes | SUPPORTED_MODES | 1 | R | [493] | 0x01 | | | |
| FFU features | FFU_FEATURES | 1 | R | [492] | 0x00 | | | |
| Operation codes timeout | OPERATION_CODE_TIMEOUT | 1 | R | [491] | 0x00 | | | |
| FFU Argument | FFU_ARG | 4 | R | [490:487] | 0xC7810000 | | | |
| Barrier support | BARRIER_SUPPORT | 1 | R | [486] | 0x00 | | | |
| Reserved ¹ | | 177 | - | [485:309] | - | | | |
| CMD Queuing Support | CMDQ_SUPPORT | 1 | R | [308] | 0x01 | | | |
| CMD Queuing Depth | CMDQ_DEPTH | 1 | R | [307] | 0x0F | | | |
| Reserved ¹ | | 1 | - | [306] | - | | | |
| Number of FW sectors correctly programmed | NUMBER_OF_FW_SECTORS_CORRECTLY_PROGRAMMED | 4 | R | [305:302] | 0x00 | | | |
| Vendor proprietary health report | VENDOR_PROPRIETARY_HEALTH_REPORT | 32 | R | [301:270] | 0x00 | | | |
| Device life time estimation type B | DEVICE_LIFE_TIME_EST_TYP_B | 1 | R | [269] | 0x01 | | | |
| Device life time estimation type A | DEVICE_LIFE_TIME_EST_TYP_A | 1 | R | [268] | 0x01 | | | |
| Pre EOL information | PRE_EOL_INFO | 1 | R | [267] | 0x01 | | | |
| Optimal read size | OPTIMAL_READ_SIZE | 1 | R | [266] | 0x00 | | | |
| Optimal write size | OPTIMAL_WRITE_SIZE | 1 | R | [265] | 0x08 | 0x10 | 0x20 | 0x20 |
| Optimal trim unit size | OPTIMAL_TRIM_UNIT_SIZE | 1 | R | [264] | 0x01 | | | |

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| | | | | | | | | |
|--|------------------------------------|---|---|-----------|---------------|---------------|---------------|----------------|
| Device version | DEVICE_VERSION | 2 | R | [263:262] | 0x00 | | | |
| Firmware version | FIRMWARE_VERSION | 3 | R | [261:254] | FW Patch Ver. | | | |
| Power class for 200MHz, DDR at VCC=3.6V | PWR_CL_DDR_200_360 | 1 | R | [253] | 0x00 | | | |
| Cache size | CACHE_SIZE | 4 | R | [252:249] | 0x10000 | | | |
| Generic CMD6 timeout | GENERIC_CMD6_TIME | 1 | R | [248] | 0x0A | | | |
| Power off notification(long) timeout | POWER_OFF_LONG_TIME | 1 | R | [247] | 0x3C | | | |
| Background operations status | BKOPS_STATUS | 1 | R | [246] | 0x00 | | | |
| Number of correctly programmed sectors | CORRECTLY_PRG_SECTORS_NUM | 4 | R | [245:242] | 0x00 | | | |
| 1st initialization time after partitioning | INI_TIMEOUT_AP | 1 | R | [241] | 0x1E | | | |
| Cache Flushing Policy | CACHE_FLUSH_POLICY | 1 | R | [240] | 0x00 | | | |
| Power class for 52MHz, DDR at 3.6V | PWR_CL_DDR_52_360 | 1 | R | [239] | 0x00 | | | |
| Power class for 52MHz, DDR at 1.95V | PWR_CL_DDR_52_195 | 1 | R | [238] | 0x00 | | | |
| Power class for 200MHz at Vccq=1.95V, Vcc=3.6V | PWR_CL_200_360 | 1 | R | [237] | 0x00 | | | |
| Power class for 200MHz, at Vccq=1.3V, Vcc=3.6V | PWR_CL_200_195 | 1 | R | [236] | 0x00 | | | |
| Minimum Write Performance for 8bit at 52MHz in DDR mode | MIN_PERF_DDR_W_8_52 | 1 | R | [235] | 0x00 | | | |
| Minimum Read Performance for 8bit at 52MHz in DDR mode | MIN_PERF_DDR_R_8_52 | 1 | R | [234] | 0x00 | | | |
| Reserved ¹ | | 1 | - | [233] | - | | | |
| TRIM Multiplier | TRIM_MULT | 1 | R | [232] | 0x02 | | | |
| Secure Feature support | SEC_FEATURE_SUPPORT | 1 | R | [231] | 0x55 | | | |
| Secure Erase Multiplier | SEC_ERASE_MULT | 1 | R | [230] | 0x1B | | | |
| Secure TRIM Multiplier | SEC_TRIM_MULT | 1 | R | [229] | 0x11 | | | |
| Boot information | BOOT_INFO | 1 | R | [228] | 0x07 | | | |
| Reserved ¹ | | 1 | - | [227] | - | | | |
| Boot partition size | BOOT_SIZE_MULT | 1 | R | [226] | 0x20 | | | |
| Access size | ACC_SIZE | 1 | R | [225] | 0x07 | | | |
| High-capacity erase unit size | HC_ERASE_GRP_SIZE | 1 | R | [224] | 0x01 | | | |
| High-capacity erase timeout | ERASE_TIMEOUT_MULT | 1 | R | [223] | 0x01 | | | |
| Reliable write sector count | REL_WR_SEC_C | 1 | R | [222] | 0x01 | | | |
| High-capacity write protect group size | HC_WP_GRP_SIZE | 1 | R | [221] | 0x10 | | | |
| Sleep current (VCC) | S_C_VCC | 1 | R | [220] | 0x07 | | | |
| Sleep current (VCCQ) | S_C_VCCQ | 1 | R | [219] | 0x07 | | | |
| Production state awareness timeout | PRODUCTION_STATE_AWARENESS_TIMEOUT | 1 | R | [218] | 0x00 | | | |
| Sleep/awake timeout | S_A_TIMEOUT | 1 | R | [217] | 0x11 | | | |
| Sleep Notification Timeout | SLEEP_NOTIFICATION_TIME | 1 | R | [216] | 0x07 | | | |
| Sector Count | SEC_COUNT | 4 | R | [215:212] | 0x1D1 F000 | 0x3A3 E000 | 0x747 C000 | 0xE- 8F6000 |
| Secure Write Protect Information | SECURE_WP_INFO | 1 | R | [211] | 0x01 | | | |
| Minimum Write Performance for 8bit at 52MHz | MIN_PERF_W_8_52 | 1 | R | [210] | 0x00 | | | |
| Minimum Read Performance for 8bit at 52MHz | MIN_PERF_R_8_52 | 1 | R | [209] | 0x00 | | | |
| Minimum Write Performance for 8bit at 26MHz, for 4bit at 52MHz | MIN_PERF_W_8_26_4_52 | 1 | R | [208] | 0x00 | | | |
| Minimum Read Performance for 8bit at 26MHz, for 4bit at 52MHz | MIN_PERF_R_8_26_4_52 | 1 | R | [207] | 0x00 | | | |

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| | | | | | |
|---|-----------------------|---|---------------------------|-------|------|
| Minimum Write Performance for 4bit at 26MHz | MIN_PERF_W_4_26 | 1 | R | [206] | 0x00 |
| Minimum Read Performance for 4bit at 26MHz | MIN_PERF_R_4_26 | 1 | R | [205] | 0x00 |
| Reserved ¹ | | 1 | - | [204] | - |
| Power class for 26MHz at 3.6V 1 R | PWR_CL_26_360 | 1 | R | [203] | 0x00 |
| Power class for 52MHz at 3.6V 1 R | PWR_CL_52_360 | 1 | R | [202] | 0x00 |
| Power class for 26MHz at 1.95V 1 R | PWR_CL_26_195 | 1 | R | [201] | 0x00 |
| Power class for 52MHz at 1.95V 1 R | PWR_CL_52_195 | 1 | R | [200] | 0x00 |
| Partition switching timing | PARTITION_SWITCH_TIME | 1 | R | [199] | 0x01 |
| Out-of-interrupt busy timing | OUT_OF_INTERRUPT_TIME | 1 | R | [198] | 0x05 |
| I/O Driver Strength | DRIVER_STRENGTH | 1 | R | [197] | 0x1F |
| Device type | DEVICE_TYPE | 1 | R | [196] | 0x57 |
| Reserved ¹ | | 1 | - | [195] | - |
| CSD structure | CSD_STRUCTURE | 1 | R | [194] | 0x02 |
| Reserved ¹ | | 1 | - | [193] | - |
| Extended CSD revision | EXT_CSD_REV | 1 | R | [192] | 0x08 |
| Modes Segment | | | | | |
| Command set | CMD_SET | 1 | R/W/ E_P | [191] | 0x00 |
| Reserved ¹ | | 1 | - | [190] | - |
| Command set revision | CMD_SET_REV | 1 | R | [189] | 0x00 |
| Reserved ¹ | | 1 | - | [188] | - |
| Power class | POWER_CLASS | 1 | R/W/ E_P | [187] | 0x00 |
| Reserved ¹ | | 1 | - | [186] | - |
| High-speed interface timing | HS_TIMING | 1 | R/W/ E_P | [185] | 0x00 |
| Strobe Support | STROBE_SUPPORT | 1 | R | [184] | 0x01 |
| Bus width mode | BUS_WIDTH | 1 | W/E_P | [183] | 0x00 |
| Reserved ¹ | | 1 | - | [182] | - |
| Erased memory content | ERASED_MEM_CONT | 1 | R | [181] | 0x00 |
| Reserved ¹ | | 1 | - | [180] | - |
| Partition configuration | PARTITION_CONFIG | 1 | R/W/E & R/W/ E_P | [179] | 0x00 |
| Boot config protection | BOOT_CONFIG_PROT | 1 | R/W & R/W/ C_P | [178] | 0x00 |
| Boot bus Conditions | BOOT_BUS_CONDITIONS | 1 | R/W/E | [177] | 0x00 |
| Reserved ¹ | | 1 | - | [176] | - |
| High-density erase group definition | ERASE_GROUP_DEF | 1 | R/W/ E_P | [175] | 0x00 |
| Boot write protection status registers | BOOT_WP_STATUS | 1 | R | [174] | 0x00 |
| Boot area write protection register | BOOT_WP | 1 | R/W & R/W/ C_P | [173] | 0x00 |
| Reserved ¹ | | 1 | - | [172] | - |

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| | | | | | |
|--|-----------------------------|----|-------------------------------------|-----------|--------------------------------|
| User area write protection register | USER_WP | 1 | R/W, R/W/ C_P &R/W/ E_P | [171] | 0x00 |
| Reserved ¹ | | 1 | - | [170] | - |
| FW configuration | FW_CONFIG | 1 | R/W | [169] | 0x00 |
| RPMB Size | RPMB_SIZE_MULT | 1 | R | [168] | 0x20 |
| Write reliability setting register | WR_REL_SET | 1 | R/W | [167] | 0x1F |
| Write reliability parameter register | WR_REL_PARAM | 1 | R | [166] | 0x14 |
| Start Sanitize operation | SANITIZE_START | 1 | W/E_P | [165] | 0x00 |
| Manually start background operations | BKOPS_START | 1 | W/E_P | [164] | 0x00 |
| Enable background operations handshake | BKOPS_EN | 1 | R/W | [163] | 0x00 |
| H/W reset function | RST_n_FUNCTION | 1 | R/W | [162] | 0x00 |
| HPI management | HPI_MGMT | 1 | R/W/ E_P | [161] | 0x00 |
| Partitioning Support | PARTITIONING_SUPPORT | 1 | R | [160] | 0x07 |
| Max Enhanced Area Size | MAX_ENH_SIZE_MULT | 3 | R | [159:157] | 0x3A3 0x747 0xE8F 0x1D1E |
| Partitions attribute | PARTITIONS_ATTRIBUTE | 1 | R/W | [156] | 0x00 |
| Partitioning Setting | PARTITION_SETTING_COMPLETED | 1 | R/W | [155] | 0x00 |
| General Purpose Partition Size | GP_SIZE_MULT | 12 | R/W | [154:143] | 0x00 |
| Enhanced User Data Area Size | ENH_SIZE_MULT | 3 | R/W | [142:140] | 0x00 |
| Enhanced User Data Start Address | ENH_START_ADDR | 4 | R/W | [139:136] | 0x00 |
| Reserved ¹ | | 1 | - | [135] | - |
| Bad Block Management mode | SEC_BAD_BLK_MGMNT | 1 | R/W | [134] | 0x00 |
| Production state awareness | PRODUCTION_STATE_AWARENESS | 1 | W/E_P | [133] | 0x00 |
| Package Case Temperature is controlled | TCASE_SUPPORT | 1 | W/E_P | [132] | 0x00 |
| Periodic Wake-up | PERIODIC_WAKEUP | 1 | R/W/E | [131] | 0x00 |
| Program CID/CSD in DDR mode support | PROGRAM_CID_CSD_DDR_SUPPORT | 1 | R | [130] | 0x01 |
| Reserved ¹ | | 2 | - | [129:128] | - |
| Vendor Specific Fields | VENDOR_SPECIFIC_FIELD | 64 | <vendor specific> | [127:64] | - |
| Native sector size | NATIVE_SECTOR_SIZE | 1 | R | [63] | 0x00 |
| Sector size emulation | USE_NATIVE_SECTOR | 1 | R/W | [62] | 0x00 |
| Sector size | DATA_SECTOR_SIZE | 1 | R | [61] | 0x00 |
| 1st initialization after disabling sector size emulation | INI_TIMEOUT_EMU | 1 | R | [60] | 0x00 |
| Class 6 commands control | CLASS_6_CTRL | 1 | R/W/ E_P | [59] | 0x00 |
| Number of addressed group to be Released | DYNCAP_NEEDED | 1 | R | [58] | 0x00 |
| Exception events control | EXCEPTION_EVENTS_CTRL | 2 | R/W/ E_P | [57:56] | 0x00 |
| Exception events status | EXCEPTION_EVENTS_STATUS | 2 | R | [55:54] | 0x00 |
| Extended Partitions Attribute | EXT_PARTITIONS_ATTRIBUTE | 2 | R/W | [53:52] | 0x00 |
| Context configuration | CONTEXT_CONF | 15 | R/W/ E_P | [51:37] | 0x00 |

IF THERE IS ANY OTHER OPERATION TO IMPLEMENT IN ADDITION TO SPECIFICATION IN THE DATASHEET OR JEDEC STANDARD, PLEASE CONTACT EACH BRANCH OFFICE OR HEADQUARTERS OF SAMSUNG ELECTRONICS.

| | | | | | |
|------------------------------------|------------------------------------|----|--------------|---------|------|
| Packed command status | PACKED_COMMAND_STATUS | 1 | R | [36] | 0x00 |
| Packed command failure index | PACKED_FAILURE_INDEX | 1 | R | [35] | 0x00 |
| Power Off Notification | POWER_OFF_NOTIFICATION | 1 | R/W/ E_P | [34] | 0x00 |
| Control to turn the Cache ON/OFF | CACHE_CTRL | 1 | R/W/ E_P | [33] | 0x00 |
| Flushing of the cache | FLUSH_CACHE | 1 | W/E_P | [32] | 0x00 |
| Control to turn the Barrier ON/OFF | BARRIER_CTRL | 1 | R | [31] | 0x00 |
| Mode config | MODE_CONFIG | 1 | R/W/ E_P | [30] | 0x00 |
| Mode operation codes | MODE_OPERATION_CODES | 1 | W/E_P | [29] | 0x00 |
| Reserved ¹ | | 2 | - | [28:27] | - |
| FFU status | FFU_STATUS | 1 | R | [26] | 0x00 |
| Pre loading data size | PRE_LOADING_DATA_SIZE | 4 | R/W/ E_P | [25:22] | 0x00 |
| Max pre loading data size | MAX_PRE_LOADING_DATA_SIZE | 4 | R | [21:18] | 0x00 |
| Product state awareness enablement | PRODUCT_STATE_AWARENESS_ENABLEMENT | 1 | R/W/E & R | [17] | 0x00 |
| Secure Removal Type | SECURE_REMOVAL_TYPE | 1 | R/W & R | [16] | 0x09 |
| Command Queue Mode Enable | CMDQ_MODE_EN | 1 | R/W/ E_P | [15] | 0x00 |
| Reserved ¹ | | 15 | - | [14:0] | - |

NOTE :

1) Reserved bits should read as "0."

8.0 AC PARAMETER

8.1 Timing Parameter

[Table 29] Timing Parameter

| Timing Parameter | | Max. Value | Unit |
|--|---------------------------------------|------------|------|
| Initialization Time (tINIT) | Normal ¹⁾ | 1 | s |
| | After partition setting ²⁾ | 3 | s |
| Read Timeout | | 100 | ms |
| Write Timeout | | 350 | ms |
| Erase Timeout | | 20 | ms |
| Force Erase Timeout | | 3 | min |
| Secure Erase Timeout | | 8 | s |
| Secure Trim step1 Timeout | | 5 | s |
| Secure Trim step2 Timeout | | 3 | s |
| Trim Timeout | | 600 | ms |
| Partition Switching Timeout (after Init) | | 1 | ms |
| Power Off Notification (Short) Timeout | | 100 | ms |
| Power Off Notification (Long) Timeout | | 600 | ms |

NOTE:

1) Normal Initialization Time without partition setting

2) Initialization Time after partition setting, refer to INI_TIMEOUT_AP in 6.4 EXT_CSD register

3) Be advised Timeout Values specified in Table above are for testing purposes under Samsung test pattern only and actual timeout situations may vary

4) EXCEPTION_EVENT may occur and the actual timeout values may vary due to user environment

8.2 Previous Bus Timing Parameters for DDR52 and HS200 mode are defined by JEDEC standard

8.3 Bus Timing Specification in HS400 mode

8.3.1 HS400 Device Input Timing

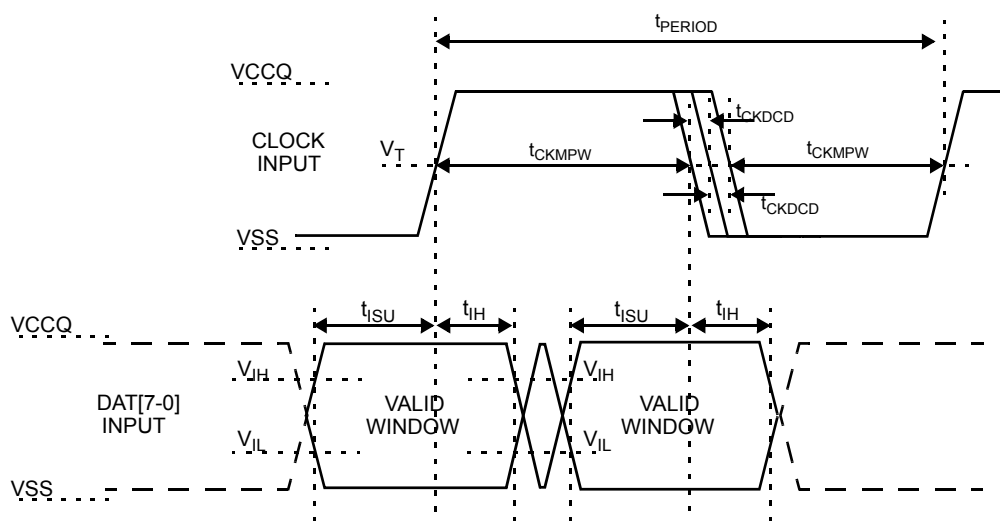


Figure 9. HS400 Device Input Timing

NOTE:

1) t_{ISU} and t_{IH} are measured at $V_{IL(max.)}$ and $V_{IH(min.)}$.

2) V_{IH} denotes $V_{IH(min.)}$ and V_{IL} denotes $V_{IL(max.)}$.

IF THERE IS ANY OTHER OPERATION TO IMPLEMENT IN ADDITION TO SPECIFICATION IN THE DATASHEET OR JEDEC STANDARD, PLEASE CONTACT EACH BRANCH OFFICE OR HEADQUARTERS OF SAMSUNG ELECTRONICS.

[Table 30] HS400 Device input timing

| Parameter | Symbol | Min | Max | Unit |
|-------------------------------|---------|-------|-----|------|
| Input CLK | | | | |
| Cycle time data transfer mode | tPERIOD | 5 | - | - |
| Slew rate | SR | 1.125 | - | V/ns |
| Duty cycle distortion | tCKDCD | 0.0 | 0.3 | ns |
| Minimum pulse width | tCKMPW | 2.2 | - | ns |
| Input DAT (referenced to CLK) | | | | |
| Input set-up time | tISUddr | 0.4 | - | ns |
| Input hold time | tIHddr | 0.4 | - | ns |
| Slew rate | SR | 1.125 | - | V/ns |

8.3.2 HS400 Device Output Timing

Data Strobe is used to read data (data read and CRC status response read) in HS400 mode. The device output value of Data Strobe is "High-Z" when the device is not in outputting data (data read, CRC status response). Data Strobe is toggled only during data read period.

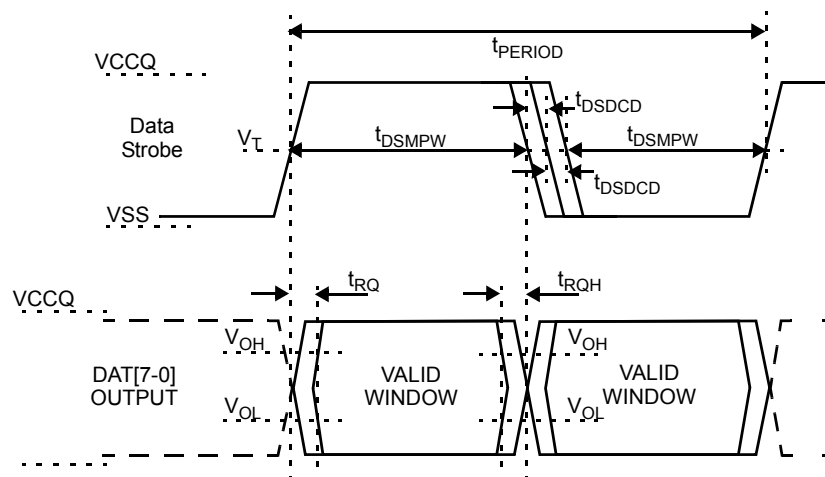


Figure 10. HS400 Device Output Timing

NOTE:

V_{OH} denotes $V_{OH(min.)}$ and V_{OL} denotes $V_{OL(max.)}$.

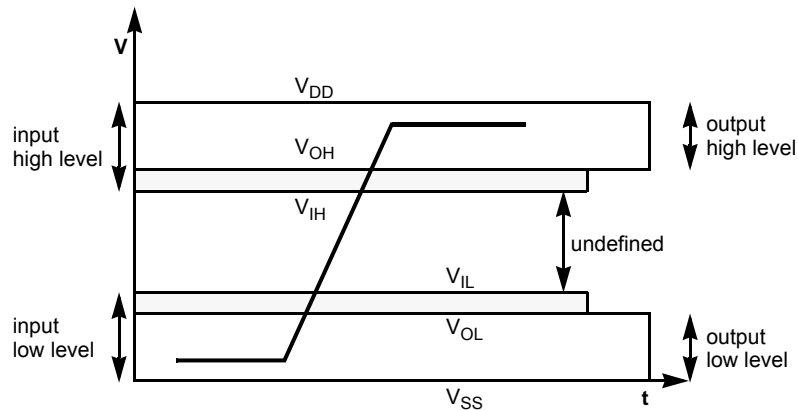
[Table 31] HS400 Device Output timing

| Parameter | Symbol | Min | Max | Unit |
|--|---------|-------|-----|---------|
| Data Strobe | | | | |
| Cycle time data transfer mode | tPERIOD | 5 | - | - |
| Slew rate | SR | 1.125 | - | V/ns |
| Duty cycle distortion | tDSDCD | 0.0 | 0.2 | ns |
| Minimum pulse width | tDSMPW | 2.0 | - | ns |
| Read pre-amble | tRPRE | 0.4 | - | tPERIOD |
| Read post-amble | tRPST | 0.4 | - | tPERIOD |
| Output DAT (referenced to Data Strobe) | | | | |
| Output skew | tRQ | - | 0.4 | ns |
| Output hold skew | tRQH | - | 0.4 | ns |
| Slew rate | SR | 1.125 | - | V/ns |

IF THERE IS ANY OTHER OPERATION TO IMPLEMENT IN ADDITION TO SPECIFICATION IN THE DATASHEET OR JEDEC STANDARD, PLEASE CONTACT EACH BRANCH OFFICE OR HEADQUARTERS OF SAMSUNG ELECTRONICS.

8.4 Bus signal levels

As the bus can be supplied with a variable supply voltage, all signal levels are related to the supply voltage.



8.4.1 Open-drain mode bus signal level

[Table 32] Open-drain bus signal level

| Parameter | Symbol | Min | Max. | Unit | Conditions |
|---------------------|----------|----------------|------|------|-------------------------|
| Output HIGH voltage | V_{OH} | $V_{DD} - 0.2$ | - | V | 1) |
| Output LOW voltage | V_{OL} | - | 0.3 | V | $I_{OL} = 2 \text{ mA}$ |

NOTE:

- 1) Because V_{oh} depends on external resistance value (including outside the package), this value does not apply as device specification. Host is responsible to choose the external pull-up and open drain resistance value to meet V_{oh} Min value.

8.4.2 Push-pull mode bus signal level eMMC

The device input and output voltages shall be within the following specified ranges for any V_{DD} of the allowed voltage range

[Table 33] Push-pull signal level—high-voltage eMMC

| Parameter | Symbol | Min | Max. | Unit | Conditions |
|---------------------|----------|-----------------------|-----------------------|------|--|
| Output HIGH voltage | V_{OH} | $0.75 \cdot V_{CCQ}$ | - | V | $I_{OH} = -100 \text{ uA}@V_{CCQ} \text{ min}$ |
| Output LOW voltage | V_{OL} | - | $0.125 \cdot V_{CCQ}$ | V | $I_{OL} = 100 \text{ uA}@V_{CCQ} \text{ min}$ |
| Input HIGH voltage | V_{IH} | $0.625 \cdot V_{CCQ}$ | $V_{CCQ} + 0.3$ | V | - |
| Input LOW voltage | V_{IL} | $V_{SS} - 0.3$ | $0.25 \cdot V_{CCQ}$ | V | - |

[Table 34] Push-pull signal level—1.70 - 1.95 V_{CCQ} voltage Range

| Parameter | Symbol | Min | Max. | Unit | Conditions |
|---------------------|----------|------------------------------------|------------------------------------|------|------------------------|
| Output HIGH voltage | V_{OH} | $V_{CCQ} - 0.45V$ | - | V | $I_{OH} = -2\text{mA}$ |
| Output LOW voltage | V_{OL} | - | 0.45V | V | $I_{OL} = 2\text{mA}$ |
| Input HIGH voltage | V_{IH} | $0.65 \cdot V_{CCQ}$ ¹⁾ | $V_{CCQ} + 0.3$ | V | - |
| Input LOW voltage | V_{IL} | $V_{SS} - 0.3$ | $0.35 \cdot V_{CCQ}$ ²⁾ | V | - |

NOTE:

- 1) $0.7 \cdot V_{CCQ}$ for MMC4.3 and older revisions.
 2) $0.3 \cdot V_{CCQ}$ for MMC4.3 and older revisions.

9.0 DC PARAMETER

9.1 Active Power Consumption during operation

[Table 35] Active Power Consumption during operation

| Density | NAND Type | CTRL | NAND | Unit |
|---------|---------------|------|------|------|
| 16 GB | 128 Gb MLC x1 | 180 | 50 | mA |
| 32 GB | 128 Gb MLC x2 | | 100 | |
| 64 GB | 128 Gb MLC x4 | | 200 | |
| 128 GB | 128 Gb MLC x8 | | | |

* Power Measurement conditions: Bus configuration =x8 @200MHz DDR

* The measurement for max RMS current is the average RMS current consumption over a period of 100ms.

9.2 Standby Power Consumption in auto power saving mode and standby state.

[Table 36] Standby Power Consumption in auto power saving mode and standby state

| Density | NAND Type | CTRL | | NAND | | Unit |
|---------|---------------|-----------|------|-----------|------|------|
| | | 25°C(Typ) | 85°C | 25°C(Typ) | 85°C | |
| 16 GB | 128 Gb MLC x1 | 120 | 400 | 40 | 85 | uA |
| 32 GB | 128 Gb MLC x2 | | | 50 | 135 | |
| 64 GB | 128 Gb MLC x4 | | | 70 | 235 | |
| 128 GB | 128 Gb MLC x8 | | | 130 | 435 | |

NOTE:

Power Measurement conditions: Bus configuration =x8, No CLK

*Typical value is measured at Vcc=3.3V, TA=25°C. Not 100% tested.

9.3 Sleep Power Consumption in Sleep State

[Table 37] Sleep Power Consumption in Sleep State

| Density | NAND Type | CTRL | | NAND | Unit |
|---------|---------------|-----------|------|-----------------|------|
| | | 25°C(Typ) | 85°C | | |
| 16 GB | 128 Gb MLC x1 | 120 | 400 | 0 ¹⁾ | uA |
| 32 GB | 128 Gb MLC x2 | | | | |
| 64 GB | 128 Gb MLC x4 | | | | |
| 128 GB | 128 Gb MLC x8 | | | | |

NOTE:

Power Measurement conditions: Bus configuration =x8, No CLK

1) In auto power saving mode , NAND power can not be turned off .However in sleep mode NAND power can be turned off. If NAND power is alive , NAND power is same with that of the Standby state.

9.4 Bus Signal Line Load

The total capacitance C_L of each line of the eMMC bus is the sum of the bus master capacitance C_{HOST} , the bus capacitance C_{BUS} itself and the capacitance C_{DEVICE} of the eMMC connected to this line:

$$C_L = C_{HOST} + C_{BUS} + C_{DEVICE}$$

The sum of the host and bus capacitances should be under 20pF.

[Table 38] Bus Signal Line Load

| Parameter | Symbol | Min | Typ. | Max | Unit | Remark |
|---------------------------------------|--------------|-----|------|-----|------|---------------------------------------|
| Pull-up resistance for CMD | R_{CMD} | 4.7 | | 100 | KOhm | to prevent bus floating |
| Pull-up resistance for DAT0-DAT7 | R_{DAT} | 10 | | 100 | KOhm | to prevent bus floating |
| Internal pull up resistance DAT1-DAT7 | R_{int} | 10 | | 150 | KOhm | to prevent unconnected lines floating |
| Single Device capacitance | C_{DEVICE} | | | 12 | pF | |
| Maximum signal line inductance | | | | 16 | nH | $f_{PP} \leq 52$ MHz |

[Table 39] Capacitance and Resistance for HS400 mode

| Parameter | Symbol | Min | Typ | Max | Unit | Remark |
|--------------------------------------|--------------------|-----|-----|-----|------|---------------|
| Bus signal line capacitance | CL | | | 13 | pF | Single Device |
| Single Device capacitance | C_{DEVICE} | | | 6 | pF | |
| Pull-down resistance for Data Strobe | $R_{Data\ Strobe}$ | 10 | | 100 | KOhm | |